

Certificate of Analysis

IARM Ni244H-18

Nickel Alloy 244H

Certified Reference Material

Certified Values listed in wt.% with associated uncertainties

Al	0.23 ± 0.02	As	0.0009 ± 0.0002	B	0.002 ± 0.002	C	0.052 ± 0.002
Co	0.005 ± 0.003	Cr	6.9 ± 0.1	Cu	0.013 ± 0.002	Fe	39.9 ± 0.1
Mg	0.0014 ± 0.0003	Mn	10.9 ± 0.1	Mo	0.003 ± 0.001	N	0.0087 ± 0.0007
Nb	0.70 ± 0.06	Ni	41.1 ± 0.3	O	0.0009 ± 0.0007	P	0.003 ± 0.002
S	0.0038 ± 0.0007	Sb	0.00012 ± 0.00004	Si	0.16 ± 0.02	Sn	0.0003 ± 0.0003
Ti	0.20 ± 0.01	V	0.004 ± 0.003	Zr	0.0008 ± 0.0008		

Indicative Values listed in ppm

Ag (<5)	Au (<1)	Ba (<1)	Be (<1)	Bi (<50)	Br (<1)	Ca (3)
Cd (<50)	Ce (<1)	Cl (<1)	Cs (<1)	Dy (<1)	Er (<1)	Eu (<1)
F (<1)	Ga (10)	Gd (<1)	Ge (10)	H (<3)	Hf (<50)	Hg (<1)
Ho (<1)	I (<1)	In (<1)	Ir (<1)	K (<1)	La (<5)	Li (<1)
Lu (<1)	Na (<1)	Nd (<1)	Os (<1)	Pb (<250)	Pd (<10)	Pr (<1)
Pt (<1)	Rb (<1)	Re (<50)	Rh (<1)	Ru (<1)	Sc (<1)	Se (<10)
Sm (<1)	Sr (<20)	Ta (10)	Tb (<1)	Te (<1)	Th (<1)	Tl (<1)
Tm (<1)	U (<1)	W (20)	Y (<10)	Yb (<1)	Zn (<3)	

Description and Intended Use

This CRM may come in the form of a solid disk, chips, or powder. The intended use of this CRM may include, but is not limited to, the calibration of instruments and the validation of analytical methods.

Instructions for Use

1. The test surface is on the opposite side of the labeled surface, which includes the material identification. The entire thickness of the unit is certified. However, the user is cautioned not to measure disks less than 2 mm thick when using X-ray fluorescence spectrometry. Each packaged disk has been prepared by finishing the test surface using a lathe. The user must determine the correct surface preparation procedure for each analytical technique. The user is cautioned to use care when either resurfacing the disk or performing additional polishing, as these processes may contaminate the surface.
2. The minimum sample size for chips should be individually evaluated based on the analytical technique used; this would typically be greater than 0.1 grams.
3. The material should be stored in a cool, dry location when not in use.
4. Chips are not certified for Oxygen analysis.

Certification Laboratories

Connecticut Metallurgical Inc.
EAG Laboratories
Massachusetts Materials Research, Inc.
Huntington Alloys, Special Metals Corporation
Haynes International, Inc.
Dirats Laboratories

East Hartford, CT
Liverpool, NY
West Boylston, MA
Huntington, WV
Kokomo, IN
Westfield, MA

Laboratory Testing Inc.
Luvak, Inc.
Northern Analytical Laboratory, Inc.
VHG Labs
IMR Test Labs
NSL Analytical Services, Inc.

Hatfield, PA
Boylston, MA
Londonderry, NH
Manchester, NH
Lansing, NY
Cleveland, OH

Certification laboratories have demonstrated performance and traceability by utilizing test methods under the scope of ISO 17025 or have shown competence through a proficiency testing program. Some of the specific CRMs and SRMs used in the analysis of the material covered by this certificate are:

NIST 349A

NIST 361

NIST 362

NIST 363

NIST 1187

IARM 55B

IARM 63B

IARM 7C

Homogeneity and Uncertainty

"Uncertainty" values, as reported adjacent to certified concentration values, are based on a 95% Confidence Interval. These estimated uncertainties include the combined effects of method imprecision, material inhomogeneity, and any bias between methods. Homogeneity data from experimental XRF results are reflected in both the overall statistics and certified data. Homogeneity samples are selected by a systematic sampling procedure. The number of samples may be determined by equation 1, where N_{prod} is the number of units produced and N_{min} is the number of samples used for homogeneity testing. These samples are arranged in a simple randomized design such that each sample is analyzed multiple times by XRF. Homogeneity may also be determined within sample using an applied version of ASTM E826. A single factor ANOVA is used to calculate uncertainty due to inhomogeneity (U_{hom}). Uncertainty of the material is calculated by equation 2, where $H=U_{hom}$, S = Standard deviation, t = t-value at 95% CI, and n = number of observations.

$$1. N_{min} = \max(10, \sqrt[3]{N_{prod}})$$

$$2. U_{CRM} = \frac{\sqrt{H^2 + S^2}}{\sqrt{n}} * t$$

Expiration

The certification of this material is valid indefinitely, within the uncertainty specified, provided the material is handled and stored in accordance with the instructions stated on this certificate. The certification is nullified if the material is damaged, contaminated, otherwise modified, or used in a manner for which it was not intended.



David Coler, General Manager

Analytical Reference Materials International



Analytical Reference Materials International • 276 Abby Road • Manchester, NH 03103
Telephone (603) 935-4100 • Fax (603) 935-4101 • www.ARMi.com • ARMI@LGCgroup.com

IARM-Ni244H-18-F

6/1/2018

3 / 3